Substitute Form PTO-1449 (Modified)

(37 CFR §1.98(b))

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 12732-061002

Application No. New Divisional **Application**

Information Disclosure Statement by Applicant (Use several sheets if necessary)

Applicant

Taketomi Asami et al.

Filing Date March 4, 2004 Group Art Unit

	1		U.S. Paten	t Documents			Filing Date
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	If Appropriate
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Examiner Signature

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Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Disclosure Form (PTO-1449)

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			Applicant Taketomi Asami e	et al.			
			Filing Date Group Art Unit 28			2815	
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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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Sheet <u>1</u> of <u>1</u>

Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. Attorney's Docket No. 12732-061002

Application No. 10/792,132

Information Disclosure Statement by Applicant (Use several sheets if necessary) Applicant Taketomi Asami et al.

March 4, 2004

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U.S. Patent Documents Publication Filing Date Examiner Desig. Document Patentee Class Subclass If Appropriate Initial ID Number Date J. 24 JAN 2002 YAMAZAKI et al. AA 2002-0008286 AB AC AD **AE** AF AG AΗ ΑI ΑJ ΑK

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Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
•	AL							
	AM							
	AN		·		/			
	AO			·				
	ΑP							

1	Other D	ocuments (include Author, Title, Date, and Place of Publication)
Examiner Initial	Desig. ID	· Document
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	AR	
	AS	
	AT	

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